Rochester Electronics Manufactured Components

Rochester branded components are manufactured using either die/wafers purchased from the original suppliers or Rochester wafers recreated from the original IP. All recreations are done with the approval of the OCM.

Parts are tested using original factory test programs or Rochester developed test solutions to guarantee product meets or exceed the OCM data sheet.

Quality Overview

- ISO-9001
- AS9120 certification
- Qualified Manufacturers List (QML) MIL-PRF-35835
    - Class Q Military
    - Class V Space Level
- Qualified Suppliers List of Distributors (QSLD)

    • Rochester is a critical supplier to DLA and meets all industry and DLA standards.

Rochester Electronics, LLC is committed to supplying products that satisfy customer expectations for quality and are equal to those originally supplied by industry manufacturers.

The original manufacturer's datasheet accompanying this document reflects the performance and specifications of the Rochester manufactured version of this device. Rochester Electronics guarantees the performance of its semiconductor products to the original OEM specifications. 'Typical' values are for reference purposes only. Certain minimum or maximum ratings may be based on product characterization, design, simulation, or sample testing.

_N_ _National_
Semiconductor

MICROCIRCUIT DATA SHEET

CN74F373-X REV 1A0

Original Creation Date: 11/18/96
Last Update Date: 06/19/97
Last Major Revision Date: 04/17/97

OCTAL TRANSPARENT LATCH WITH TRI-STATE OUTPUTS

General Description

The F373 consists of eight latches with Tri-State outputs for bus organized system applications. The flip-flops appear transparent to the data when Latch Enable (LE) is HIGH. When LE is LOW, the data that meets the setup times are latched. Data appear on the bus when the Output Enable ($\overline{OE}$) is LOW. When $\overline{OE}$ is HIGH, the bus output is in the high impedance state.

Industry Part Number

74F373

NS Part Numbers

74F373DC

Prime Die

M373

Processing

Quality Conformance Inspection

Subgrp	Description	Temp (°C)
1	Static tests at	+25
2	Static tests at	+70
3	Static tests at	0
4	Dynamic tests at	+25
5	Dynamic tests at	+70
6	Dynamic tests at	0
7	Functional tests at	+25
8A	Functional tests at	+70
8B	Functional tests at	0
9	Switching tests at	+25
10	Switching tests at	+70
11	Switching tests at	0

Features

- Tri-State Outputs for Bus Lines Interfacing
- Eight Latches in a single package
- Guaranteed 4000V minimum ESD protection

(Absolute Maximum Ratings)
(Note 1)

Storage Temperature	-65 C to +150 C
Ambient Temperature under Bias	-55 C to +125 C
Junction Temperature under Bias	-55 C to +175 C
Vcc Pin Potential to Ground Pin	-0.5V to +7.0V
Input Voltage (Note 2)	-0.5V to +7.0V
Input Current (Note 2)	-30mA to +5.0mA
Voltage Applied to Output in HIGH State (with Vcc=0V)	
Standard Output	-0.5V to Vcc
TRI-STATE Output	-0.5V to +5.5V
Current Applied to Output in LOW State (Max)	twice the rated Iol(mA)
ESD Last Passing Voltage (Min)	4000V

Note 1: Absolute Maximum ratings are those values beyond which the device may be damaged or have its useful life impaired. Functional operation under these conditions is not implied.
Note 2: Either voltage limit or current limit is sufficient to protect inputs.

Recommended Operating Conditions

Free Air Ambient Temperature	
Commercial	0 C to +70 C
Supply Voltage	
Commercial	+4.5V to +5.5V

Electrical Characteristics

DC PARAMETERS

(The following conditions apply to all the following parameters, unless otherwise specified.)
DC: VCC 4.5V to 5.5V, Temp range: 0C to +70C

SYMBOL	PARAMETER	CONDITIONS	NOTES	PIN-NAME	MIN	MAX	UNIT	SUB-GROUPS
VIH	Input HIGH Voltage	Recognized as a HIGH Signal	1	INPUTS	2.0		V	1, 2, 3
VIL	Input LOW Voltage	Recognized as a LOW Signal	1	INPUTS		0.8	V	1, 2, 3
VCD	Input Clamp Diode Voltage	VCC=4.5V, IIN=-18mA	2, 3	INPUTS		-1.2	V	1, 2, 3
VOH	Output HIGH Voltage	VCC= 4.5V, IOH=-1.0mA	2, 3	OUTPUTS	2.5		V	1, 2, 3
		VCC= 4.5V, IOH=-3.0mA	2, 3	OUTPUTS	2.4		V	1, 2, 3
		VCC= 4.75V, IOH=-1.0mA	2, 3	OUTPUTS	2.7		V	1, 2, 3
		VCC= 4.75V, IOH=-3.0mA	2, 3	OUTPUTS	2.7		V	1, 2, 3
VOL	Output LOW Voltage	VCC=4.5V, IOL=24mA	2, 3	OUTPUTS		0.5	V	1, 2, 3
IIH	Input HIGH Current	VCC=5.5V, VIN=2.7V	2, 3	INPUTS		5.0	uA	1, 2, 3
IBVI	Input HIGH Current Breakdown Test	VCC=5.5V, VIN=7.0V	2, 3	INPUTS		7.0	uA	1, 2, 3
ICEX	Output HIGH Leakage Current	VCC=5.5V, VOUT = VCC	2, 3	OUTPUTS		100	uA	1, 2, 3
VID	Input Leakage Test	VCC = 0.0V, IID = 1.9uA, All other pins grounded	2, 3	INPUTS	4.75		V	1, 2, 3
IOD	Output Leakage Circuit Current	VCC = 0.0V, VIOD = 150mV, All other pins grounded	2, 3	OUTPUTS		4.75	uA	1, 2, 3
IIL	Input LOW Current	VCC=5.5V, VIN=0.5V	2, 3	INPUTS		-0.6	mA	1, 2, 3
IOZH	Output Leakage Current	VCC=5.5V, VOUT=2.7V	2, 3	OUTPUTS		50	uA	1, 2, 3
IOZL	Output Leakage Current	VCC=5.5V, VOUT=0.5V	2, 3	OUTPUTS		-50	uA	1, 2, 3
IOS	Output Short Circuit Current	VCC=5.5V, VOUT = 0V	2, 3	OUTPUTS	-60	-150	mA	1, 2, 3
IZZ	Bus Drainage Test	VCC = 0.0V, VOUT = 5.25V	2, 3			500	uA	1, 2, 3
ICCZ	Power Supply Current	VCC=5.5V, VO = HIGH Z	2, 3	VCC		55	mA	1, 2, 3

Electrical Characteristics

AC PARAMETERS

(The following conditions apply to all the following parameters, unless otherwise specified.)
AC: CL=50pf, RL=500 OHMS, TR=2.5ns, TF=2.5ns SEE AC FIGS. Temp Range: 0C to +70C

SYMBOL	PARAMETER	CONDITIONS	NOTES	PIN-NAME	MIN	MAX	UNIT	SUB-GROUPS
tpLH(1)	Propagation Delay	VCC=+5.0V @ +25C, VCC=4.5V & 5.5V @ 0/+70C	2, 3	Dn to On	3.0	7.0	ns	9
			2, 3	Dn to On	3.0	8.0	ns	10, 11
tpHL(1)	Propagation Delay	VCC=+5.0V @ +25C, VCC=4.5V & 5.5V @ 0/+70C	2, 3	Dn to On	2.0	5.0	ns	9
			2, 3	Dn to On	2.0	6.0	ns	10, 11
tpLH(2)	Propagation Delay	VCC=+5.0V @ +25C, VCC=4.5V & 5.5V @ 0/+70C	2, 3	LE to On	5.0	11.5	ns	9
			2, 3	LE to On	5.0	13.0	ns	10, 11
tpHL(2)	Propagation Delay	VCC=+5.0V @ +25C, VCC=4.5V & 5.5V @ 0/+70C	2, 3	LE to On	3.0	7.0	ns	9
			2, 3	LE to On	3.0	8.0	ns	10, 11
tpZH	Output Enable Time	VCC=+5.0V @ +25C, VCC=4.5V & 5.5V @ 0/+70C	2, 3	$\overline{OE}$ to On	2.0	11.0	ns	9
			2, 3	$\overline{OE}$ to On	2.0	12.0	ns	10, 11
tpZL	Output Enable Time	VCC=+5.0V @ +25C, VCC=4.5V & 5.5V @ 0/+70C	2, 3	$\overline{OE}$ to On	2.0	7.5	ns	9
			2, 3	$\overline{OE}$ to On	2.0	8.5	ns	10, 11
tpHZ	Output Disable Time	VCC=+5.0V @ +25C, VCC=4.5V & 5.5V @ 0/+70C	2, 3	$\overline{OE}$ to On	1.5	6.5	ns	9
			2, 3	$\overline{OE}$ to On	1.5	7.5	ns	10, 11
tpLZ	Output Disable Time	VCC=+5.0V @ +25C, VCC=4.5V & 5.5V @ 0/+70C	2, 3	$\overline{OE}$ to On	1.5	5.0	ns	9
			2, 3	$\overline{OE}$ to On	1.5	6.0	ns	10, 11
ts(H/L)	Setup Time HIGH or LOW	VCC=+5.0V @ +25C, VCC=4.5V & 5.5V @ 0/+70C	4	Dn to LE	2.0		ns	9, 10, 11
th(H/L)	Hold Time HIGH or LOW	VCC=+5.0V @ +25C, VCC=4.5V & 5.5V @ 0/+70C	4	Dn to LE	3.0		ns	9, 10, 11
tw(H)	Pulse Width HIGH	VCC=+5.0V @ +25C, VCC=4.5V & 5.5V @ 0/+70C	4	LE	6.0		ns	9, 10, 11

Note 1: Guaranteed by applying specific input condition and testing VOL & VOH.
Note 2: Screen tested 100% on each device at +75C temperature only, subgroups A2 & A10.
Note 3: Sample tested (Method 5005, Table 1) on each MFG. lot at +75C temperature only, subgroups A2 & A10.

(Continued)

Note 4:   Guaranteed but not tested.

Revision History

Rev	ECN #	Rel Date	Originator	Changes
1A0	M0001305	06/19/97	Donald B. Miller	